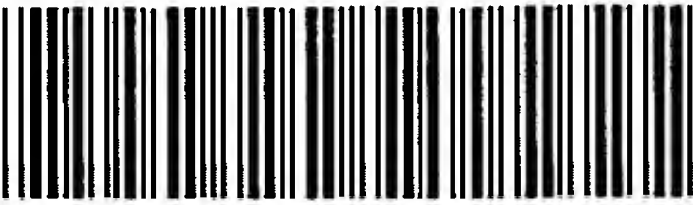


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/707,277	CHEN ET AL.	
	Examiner	Art Unit	
	Alan S. Chen	2182	

SEARCHED			
Class	Subclass	Date	Examiner
710	8	5/2/2006	ASC
↓	20	↓	↓
↓	22	↓	↓
↓	62	↓	↓
↓	72	↓	↓
713	1	↓	↓
↓	2	↓	↓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
see search history printouts			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT PLUS; Inventor Search	5/2/2006	ASC
Tanh Nguyen	5/2/2006	ASC